

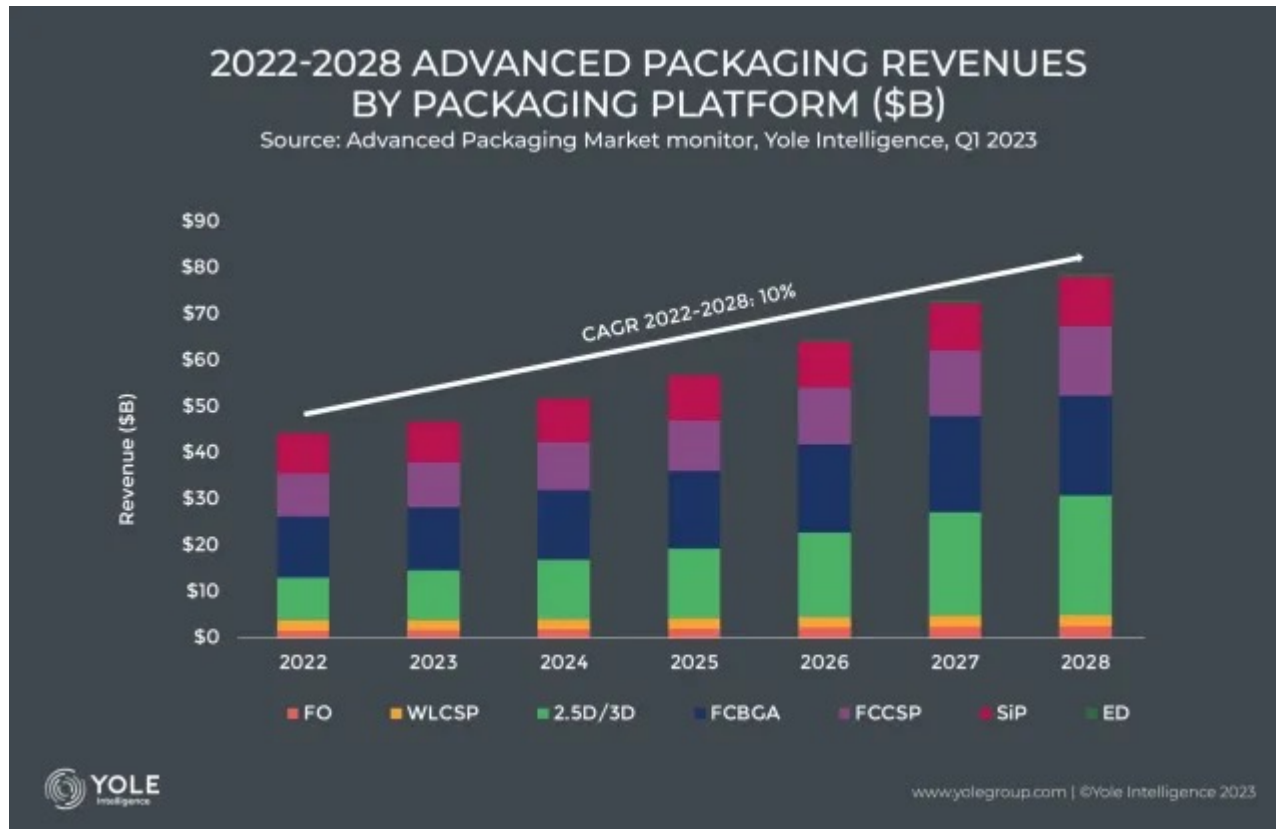
Enabling System Design in 3D Integration: Technologies and Methodologies

ISPD 2024

Hung-Ming Chen

**Institute of Electronics and SoC Center
National Yang Ming Chiao Tung University
Taiwan**

Advanced Packaging Trending



■ Why advanced packaging?

- ◆ M-chip production cost increase; disaggregating design rewarding; high-NA EUV

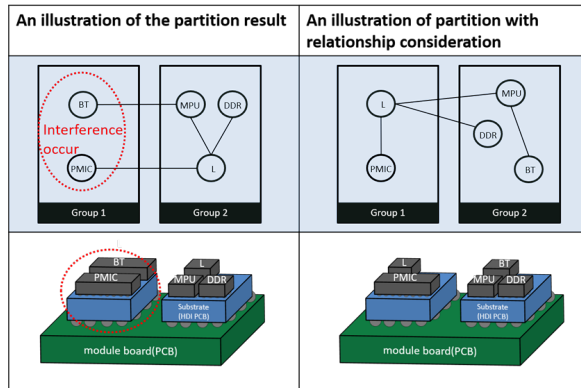
Outline

- Technology evolution in packaging manufacturing
- Methodologies in advanced packaging realization
- Chiplet the savior?
- Final remarks

Previously on the Last Episode

Three conceptual observations to paving the way to easier 3D system prototyping and implementation

- IP becomes a critical issue when chiptletizing the system: reuse or disaggregation/decomposition
 - Monolithic die can be decomposed into functional blocks or reorganized with other dies
- In the high-speed or frequency system, devices packed in a package or placed closely may cause degraded performance or dysfunction. Cut-only partition is not enough.

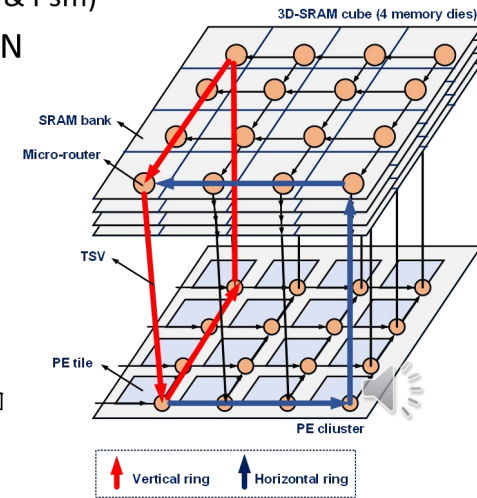
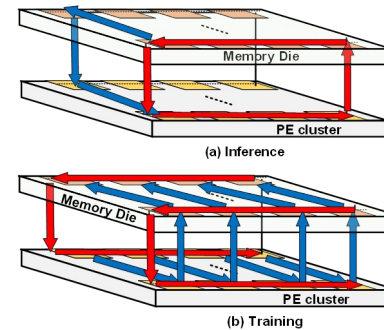


3D cross-ring interconnection architecture

- Vertical rings (for IFM & Psm)
- Horizontal rings (for weight & Psm)

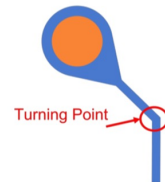
Efficient Dataflow for DNN

- Inference
- Training



(a) The offset vias that occupy the same region in each layer.

(b) The offset vias that will not route back to the same region in prior layers.



(b) Teardrop structure. A metal is shrunk from via to the wire. The turning point may suffer from stress problem.




Figure 6: Offset vias (stagger vias) are the vias in which any two adjacent layers will not overlap.

Packaging Technology Evolution

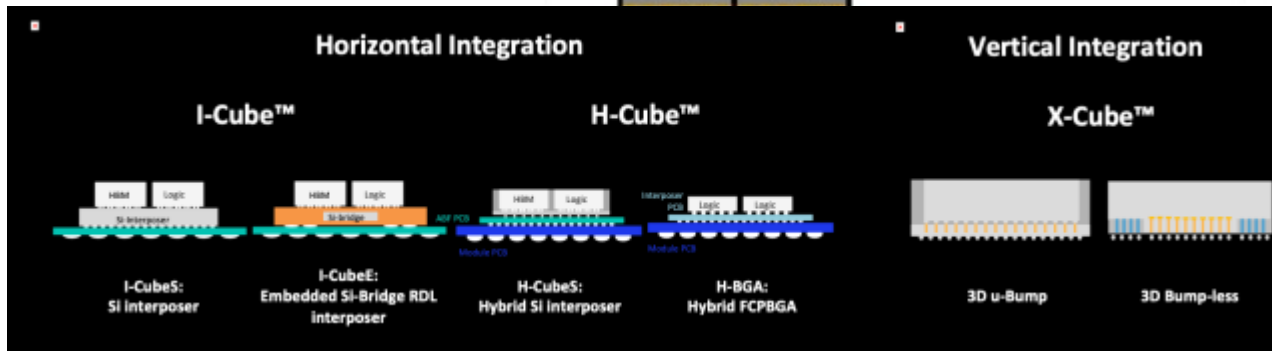
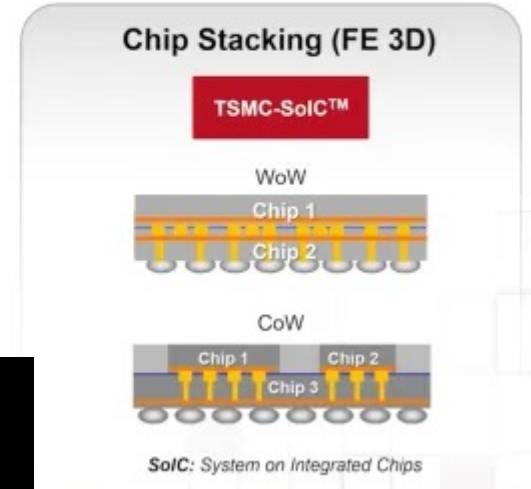
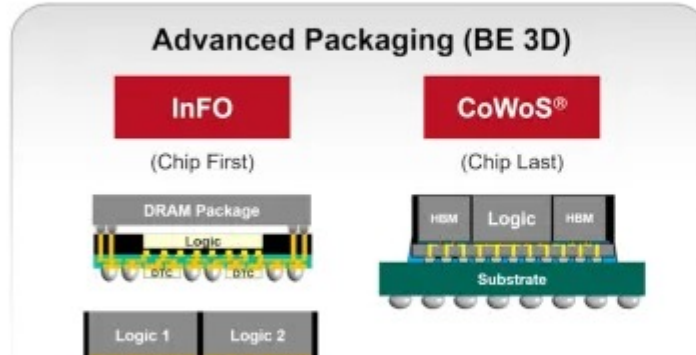
- The conventional packaging usually happens after getting the bare dies from the wafer sawing. This covers PTH/DIP, QFP, BGA.
- The first single chip microprocessor (1971) has the density around 19000 transistors/cm². Ratio of IC to package level integration was roughly around 2000:1.
- Early 1990s, the transistor density is around 265000 transistors/cm², this translates to that ratio is around 5000:1.
- In 1998 Intel's Pentium III introduced the ratio of IC to package level integration grew to more than 0.5M:1, and BGA packages emerged.
 - ◆ Transition from **computing** to **mobility**
- Advancing to **HPC and AI** era

Advanced Packaging for HPC and AI

Packaging Evolution at Intel

2D/MCP	2.5D	2.5D/3D	Hybrid Bonding	Next Gen Interconnects
FCBGA/FCLGA	Embedded Multi-die Interconnect (EMIB)	Foveros	Foveros Direct	Glass Core Substrate Co Packaged Optics
				
bump pitch ~100µm	bump pitch 55→45 →45/36µm w/TSV	bump pitch		
<ul style="list-style-type: none"> Leading global user/ assembler of FCBGA (>40% global share)* Support to 92x92mm size → >100x100mm Enabled STIM w/BGA 	<ul style="list-style-type: none"> Products shipping since 2017 High bandwidth / HBM Supports large form factor: 4.5x reticle equiv. → 6x+ reticle equiv. 	<ul style="list-style-type: none"> First prod HVM ready Wafer-level packaging Optimized cost/performance 		


Assembly Test Technology Development



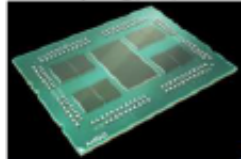
From HIR Roadmap

Parameter	Unit	2025	2027	2029
Silicon Node	nm	3nm	2nm	1nm
I/O Bandwidth (Logic-HBM)	Gbps	1024 x 2.4	2048 x 3.6	4096 x 6.4
I/O per mm per layer (shoreline)	#	250	500	1000
I/O lines and spaces (and vias)	micron	2/2/2	1/1/1	0.5/0.5/0.5
Package to Board I/O BW	Gbps	64 per I/O	112 per I/O	256 per I/O
Package to Board Pin Count	#	9600	11200	12800
Power Density	W/mm ²	1	1.05	1.1
Package Dimension (Minimum)	mm	95	103	120

1 TSV, Si Interposers



Substrates (Org/Si/Glass)




2 Microbump, solder TCB

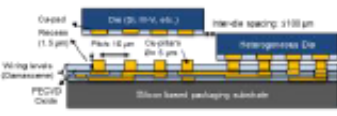
	Sn/Pb Cu Bump	Pb-Free Cu Bump	Cu Pillar + Pb-free Cap	Cu-p Pillar + Pb-free Cap
Structure				
Diameter	75 - 200 μm	75 - 150 μm	50 - 150 μm	10 - 30 μm

Old Technology → Current Technology → Next-Generation Technology

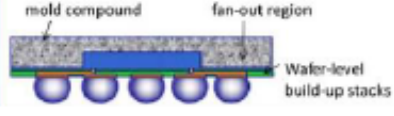
Cu-Cu Hybrid Bonding



Cu-Cu direct TCB



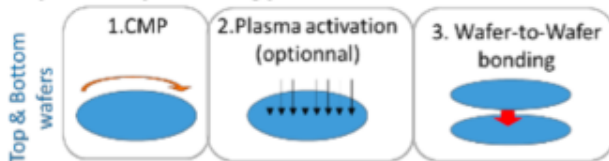
3 Fan-out WLP & PLP



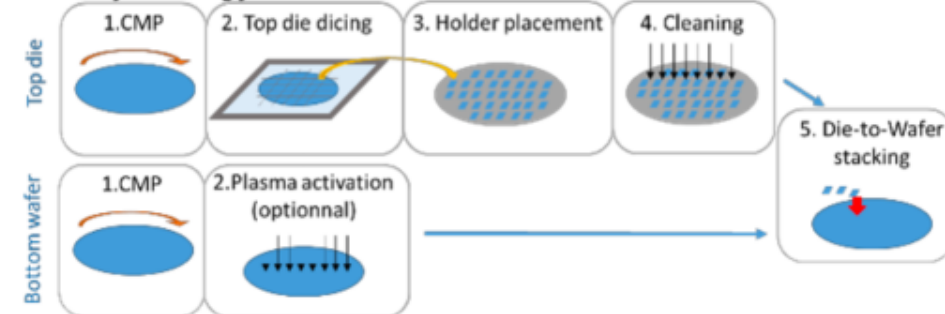
Technologies Snapshots

- Mainstream: Intel EMIB; TSMC SoIC; FOWLP
- Interposer (2.5D): costly, like PCB but more wires; secondary substrate
- Cu-to-Cu direct bonding (TCB) vs. Hybrid bonding
 - ◆ Two key differences: 40um and W2W/D2W

Wafer-to-Wafer bonding flow



Die-to-Wafer bonding flow



DTW process challenges :

Introduction of

- Dicing & cleaning
- Die handling
- Die alignment

with respect of :

surface cleanliness & nanotopography

Technologies Snapshots

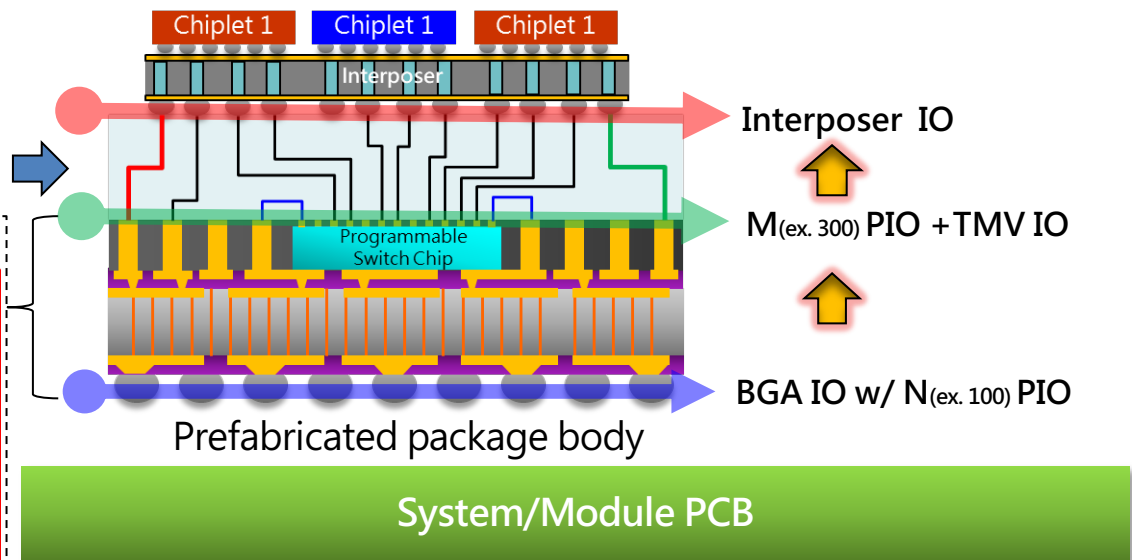
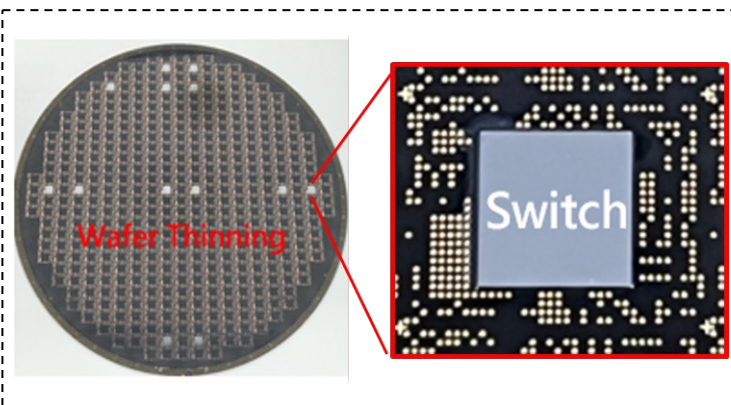
■ Issues on the table

- ◆ Reliability issues: homogeneous and heterogeneous integration, interposer material and warpage
- ◆ Should have ability to integrate the right thermal features to define the physical envelope (i.e. form factor and number of die/die stacks that can be integrated on the package)
- ◆ Bond pitch scaling for die-to-die, die-to-interposer and die-to-substrate (microbumping) interconnections
- ◆ Possible to use standard packaging to achieve ap: scale down the pitch and solve crosstalk (for high performance)

Introducing Alternative Solution

The package body is pre-designed and fabricated for 3D-IC rapid prototyping.

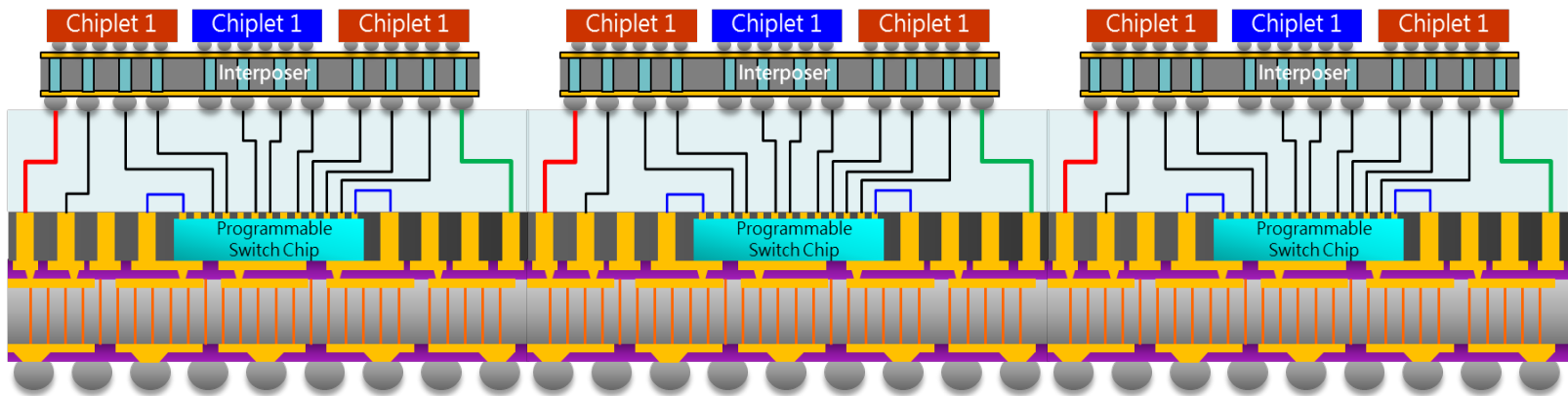
Customized Routing Layer to fit in the footprint of Interposer



Taiwan ITRI's Prefabricated Package Service

Key features:

1. Rapid prototyping is achieved by employing a pre-designed and prefabricated package body with flexible, customized routing layers tailored to the net connection requirements of 3D-IC.
2. This serves as a rapid prototyping platform to accommodate high-density interconnection interposers or chiplets.
3. The PI/SI performance of the prefabricated package can be meticulously designed and verified
4. Furthermore, the scalability of the prefabricated package body can be implemented through cascading single units."

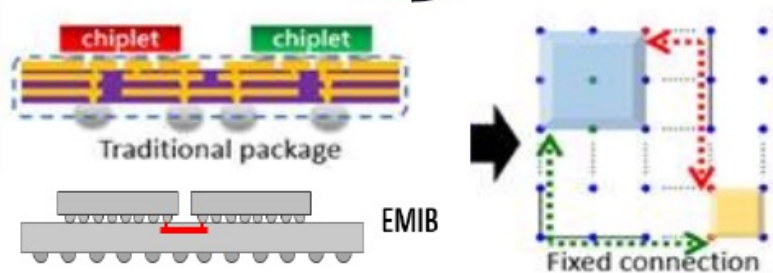


Programmable Packaging

- Pre-fabricated substrate (size/function scalable)
- Patented embedded switching chips
- One-layer redistribution to meet different applications (infrastructure)

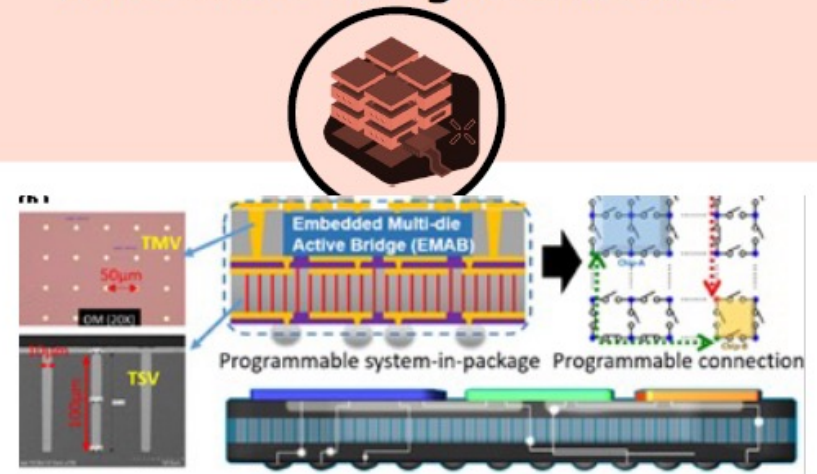
Current/State-of-Art

Intel
Amkor



- regular design, fixed interconnect (w/o programmable) and MP
- less flexibility for same approach

Innovative design/structure



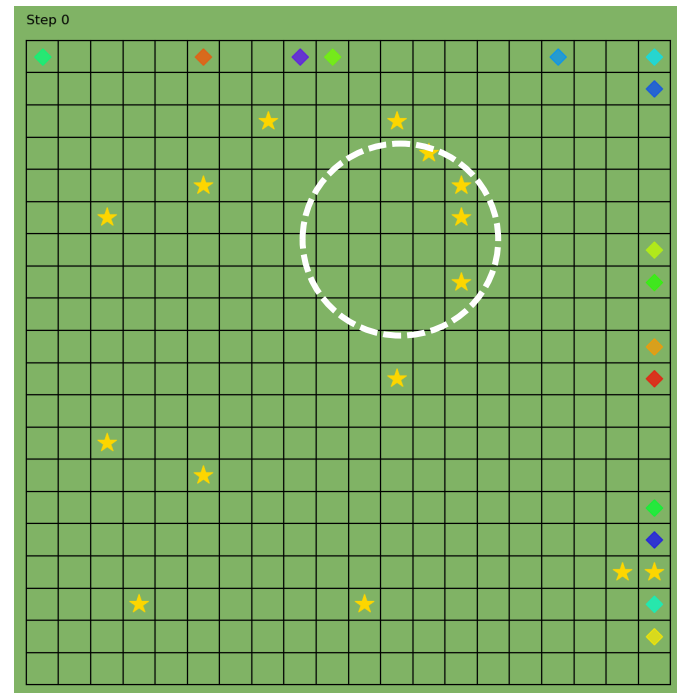
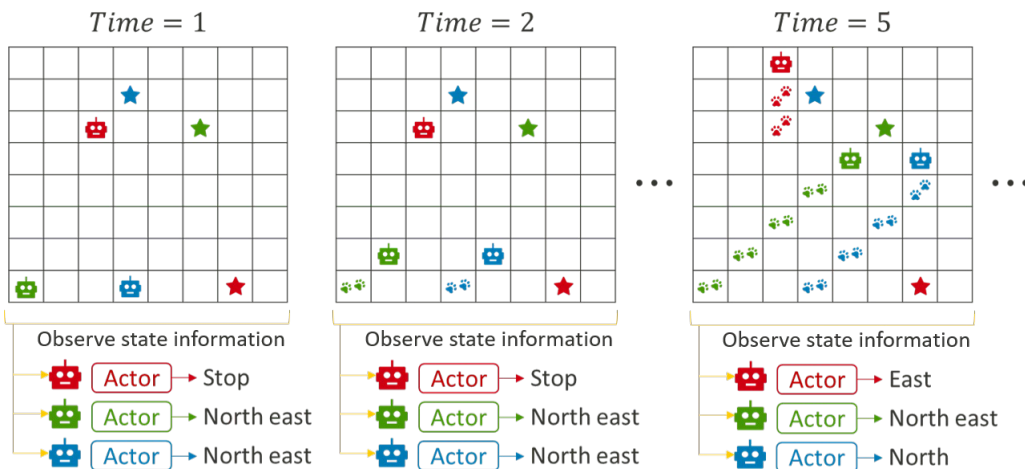
- Innovative achievement for AIoT
- 2022 IEEE Symposium on VLSI
- Prototyping and time-to-market

Methodologies/Tools Snapshots

- Main focuses: RDL synthesis, chiplet placement, and thermal awareness physical design and simulation
- We are currently working on the following tasks
 - ◆ ML-based routing and SI-awareness on D2D and substrate
 - ◆ Programmable package layout design

Multi-Agent Package Router by Learning

- Multi-net concurrent routing
 - We built deep learning models to deal with net order problem on concurrent maze routing.
 - Observing features of environment, each agent performs an action at every time step that will maximize future rewards.



Source: Yeh et al ASPDAC 2023

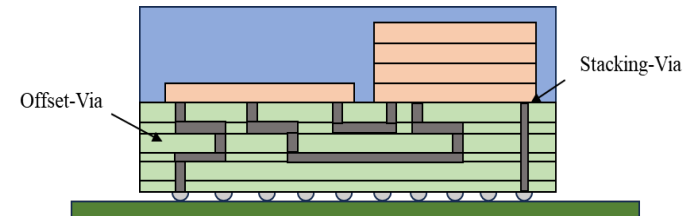
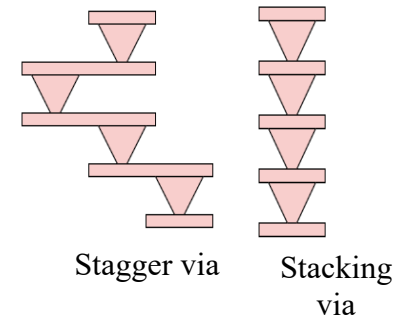
SI-Aware Customized D2D Routing

■ InFO constraints

- ◆ Staggered via can reduce the line stress on via due to multi-layer RDLs
- ◆ Improve the RDL integrity, and less prone to cracks compared to stacking via
- ◆ Induces large area, routing resource decreases and routing difficulty increases
- ◆ [6] shows that 4-tiers stacking via suffers 45% more line strain than stagger via
- ◆ Due to the fine pitch line width for routing, teardrop can make the signal more smooth
- ◆ Teardrop can reduce the crack between via and signal

■ Preliminary results

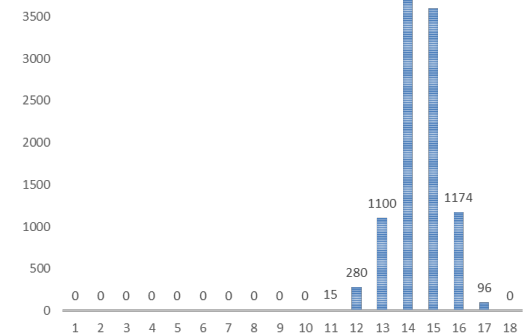
- ◆ Single layer and 2-layer interconnect shielding are studied and SI is improved by ML/DNN
- ◆ Routing resource is upper bounded by our method, and new style will be proposed



[6] Y. Chiang, S. Tai, W. Wu, J. Yeh, C. Wang, and C. Douglas, "Info_0s (integrated fan-out on substrate) technology for advanced chiplet integration," in 2021 IEEE 71st Electronic Components and Technology Conference (ECTC). IEEE, 2021, pp. 130–135.

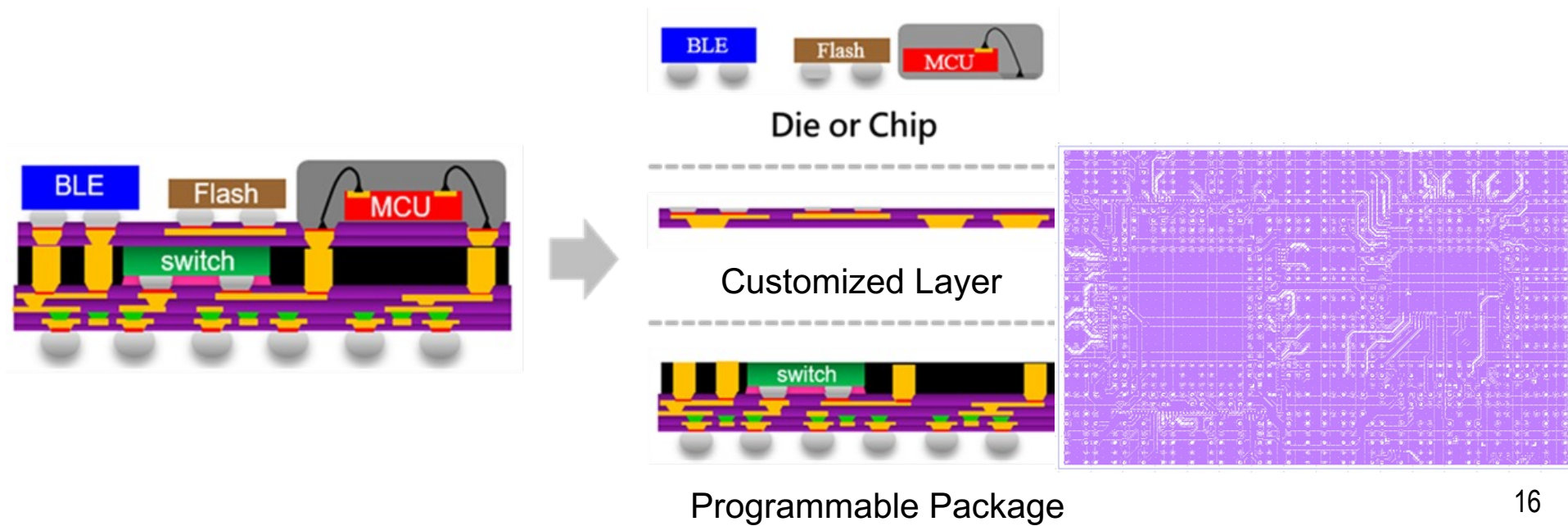


Bump and its offset via Bump and its teardrop



Problems on Customized Layer Design

- Pin assignment between the programmable package and target chiplets
- Minimize the number of layers in the customized layer for cost reduction



Chiplets the Savior in System Implementation?

- Modular architecture/building block-based methods applicable?
- IP implementation becomes more difficult, many boundary conditions and technology-dependent issues (not good for fast migration)
 - ◆ When you don't fully know the boundary conditions, you may have to over-design to make it reusable
- One needs to worry about chiplet/dielet warehousing. Chiplet mechanical and electrical standards are also essential.
- We need to generate physical, mechanical and thermal guardrails by developing modular packaging and chiplet designs based on modular domain-specific reference architectures.

Implementation Standards Efforts

- The use of standards can make it more feasible for multiple companies to create chiplet-based products.
- Current efforts on standards
 - ◆ D2D protocol (parallel): BoW, UCle (for both laminate and advanced packaging technologies), SuperCHIPS, HBM (for DRAM)
 - ◆ Physical description
 - Chiplet-based design requires models of the physicals of chiplets to be available in an EDA tool flow for package design. These models need to capture the size, thermal information, power distribution, dynamic behavior (power model), power and signal integrity and other attributes relevant to package design.
 - Representatives: *TSMC 3Dblox*, CDXML
 - ◆ Test and verification: need more efforts

Standards for System Designs

- Standard will be good for testing, verification for chiplets will also become easy, but system verification becomes extremely difficult
- The industry is trying to reduce the burden at the system level by having standards, so that each designer or group can adhere to the standards, and then the assembly at the system level becomes much more convenient.
- Disaggregation has become necessary for some companies, either because of design size or for manufacturability issues. (also chiplet discovery)
- Within a scaled down assembled system, fine pitch interconnects make inter dielet communication simple using energy efficient protocols such as SuperCHIPS

Final Remarks

- HPC/AI systems suitable in advanced packaging:
LLM, IMC
- System technology co-design (STCO) for lower cost and higher performance
 - ◆ How to realize the system under appropriate cost: system architect needed
 - ◆ IP/chiplet business and preparation are a must
- Predictive modeling for systems? Constraining upfront
 - ◆ Advanced packaging design cost-feasibility study